

January 1995 Revised May 1999

# 74F2240 Octal Buffer/Line Driver with 25 $\Omega$ Series Resistors in the Outputs

#### **General Description**

The 74F2240 is an inverting octal buffer and line driver designed to drive capacitive inputs of MOS memory devices, address and clock lines or act as a low undershoot general purpose bus driver.

The  $25\Omega$  series resistor in the outputs reduces undershoot and ringing and eliminates the need for external resistors.

#### **Features**

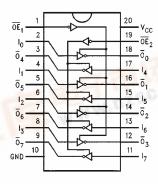
- 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs sink 12 mA and source 15 mA
- $\blacksquare$  25 $\Omega$  series resistors in outputs eliminate the need for external resistors
- Designed to drive the capacitive inputs of MOS devices
- Guaranteed 4000V minimum ESD protection

#### **Ordering Code:**

Order Number	Package Number	Package Description
74F2240SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F2240QC	V20A	20-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.350 Square

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

#### **Connection Diagram**



#### **Truth Table**

OE <sub>1</sub>	D <sub>1n</sub>	O <sub>1n</sub>	OE <sub>2</sub>	D <sub>2n</sub>	O <sub>2n</sub>	
Н	X	Z	Н	X	Z	
L	Н	H L L		Н	L	
L	L	Н	L	L	Н	

#### **Unit Loading/Fan Out**

Pin	December 1	U.L.	Output	
Names	Description	HIGH/LOW	I <sub>OH</sub> /I <sub>OL</sub>	
$\overline{\text{OE}}_1$ , $\overline{\text{OE}}_2$	3-STATE Output			
	Enable Input	1.0/1.667	20 μA/–1 mA	
	(Active LOW)	198	一工布	
I <sub>0</sub> - I <sub>7</sub>	Inputs	1.0/1.667	20 μA/–1 mA	
$\overline{O}_0 - \overline{O}_7$	Outputs	750/20	-15 mA/12 mA	

#### **Absolute Maximum Ratings**(Note 1)

Storage Temperature  $-65^{\circ}\text{C to} + 150^{\circ}\text{C}$ 

 $\begin{tabular}{lll} Ambient Temperature under Bias & -55^{\circ} to +125^{\circ} C \\ Junction Temperature under Bias & -55^{\circ} C to +150^{\circ} C \\ \end{tabular}$ 

 $V_{CC}$  Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

In HIGH State (with  $V_{CC} = 0V$ )

 $\begin{array}{ll} \text{Standard Output} & -0.5 \text{V to V}_{\text{CC}} \\ \text{3-STATE Output} & -0.5 \text{V to } +5.5 \text{V} \end{array}$ 

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA) ESD Last Passing Voltage (Min) 4000V

## **Recommended Operating Conditions**

Free Air Ambient Temperature 0°C to 70°C Supply Voltage +4.5V to +5.5V

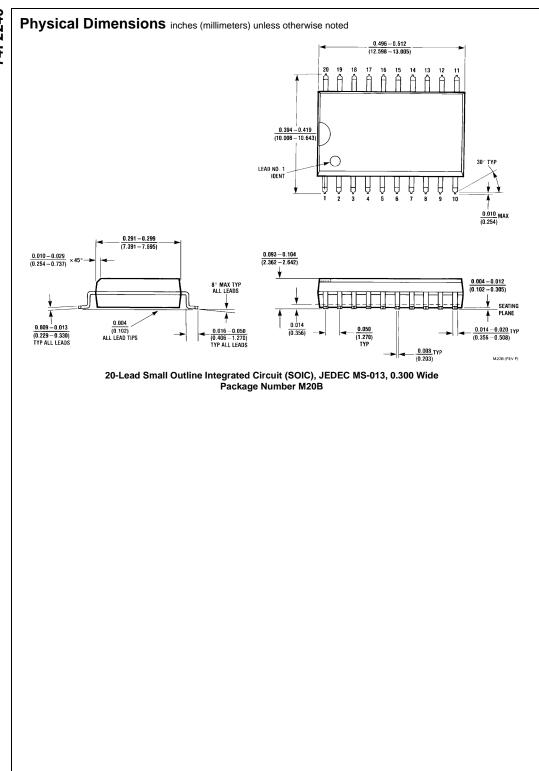
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

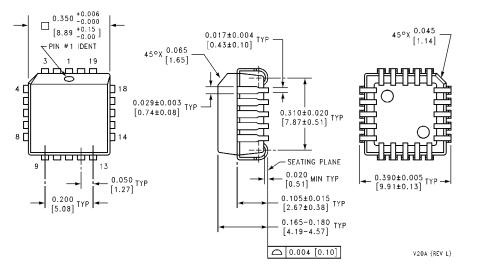
Symbol Parameter		Min	Тур	Max	Units	V <sub>cc</sub>	Conditions	
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$V_{IH}$	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage	)			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.4			V	Min	$I_{OH} = -3 \text{ mA}$
	Voltage	10% V <sub>CC</sub>	2.0			v	IVIIII	$I_{OH} = -15 \text{ mA}$
V <sub>OL</sub>	Output LOW Voltage	10% V <sub>CC</sub>			0.75	V	Min	I <sub>OL</sub> = 12 mA
I <sub>IH</sub>	Input HIGH Current				5.0	μΑ	Max	V <sub>IN</sub> = 2.7V
I <sub>BVI</sub>	Input HIGH Current Breakdown Test				7.0	μΑ	Max	V <sub>IN</sub> = 7.0V
I <sub>CEX</sub>	Output HIGH Leakage Current				50	μΑ	Max	V <sub>OUT</sub> = V <sub>CC</sub>
V <sub>ID</sub>	Input Leakage		4.75		V	0.0	$I_{ID} = 1.9 \mu A$	
	Test					\ \ \	0.0	All Other Pins Grounded
I <sub>OD</sub>	Output Leakage				3.75	μА	0.0	V <sub>IOD</sub> = 150 mV
	Circuit Current			All Other Pins Grounded				
I <sub>IL</sub>	Input LOW				-1.0		Max	V <sub>IN</sub> = 0.5V
	Current			mA		$(\overline{OE}_1, \overline{OE}_2, D_n)$		
I <sub>OZH</sub>	Output Leakage Current				50	μΑ	Max	V <sub>OUT</sub> = 2.7V
I <sub>OZL</sub>	Output Leakage Current				-50	μΑ	Max	V <sub>OUT</sub> = 0.5V
los	Output Short-Circuit Curre	nt	-100		-225	mA	Max	V <sub>OUT</sub> = 0V
I <sub>ZZ</sub>	Bus Drainage Test				500	μΑ	0.0	V <sub>OUT</sub> = 5.25V
I <sub>CCH</sub>	Power Supply Current			16	29	mA	Max	V <sub>O</sub> = HIGH
I <sub>CCL</sub>	Power Supply Current			47	75	mA	Max	$V_O = LOW$
I <sub>CCZ</sub>	Power Supply Current		•	45	63	mA	Max	$V_O = HIGH Z$

### **AC Electrical Characteristics**

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = 0$ °C to $+70$ °C $V_{CC} = +5.0V$ $C_L = 50$ pF		Units	
		Min	Тур	Max	Min	Max	†	
t <sub>PLH</sub>	Propagation Delay	3.0	4.9	7.5	3.0	7.5		
t <sub>PHL</sub>	Data to Output	2.0	3.7	6.0	2.0	6.0	ns	
t <sub>PZH</sub>	Output Enable Time	2.0	3.9	6.5	2.0	7.0	ns	
$t_{PZL}$		4.0	6.7	9.5	4.0	10.0	115	
t <sub>PHZ</sub>	Output Disable Time	2.0	4.1	6.5	2.0	7.0	ne	
$t_{PLZ}$		2.0	4.9	8.5	2.0	9.5	ns	



#### Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



20-Lead Plastic Lead Chip Carrier (PLCC), JEDEC MO-047, 0.350 Square Package Number V20A

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